



**DOUBLE BEAM UV-VIS SPECTROPHOTOMETER
LD-LUS-B20**

Double Beam UV-Vis Spectrophotometer LD-LUS-B20

Double Beam UV-Vis Spectrophotometer LD-LUS-B20 is a double beam designed UV-Vis spectrophotometer, offers 190 to 1100 nm of wavelength range with C-T monochromator and 1600 L/mm holographic grating. Features 3D spectrogram measurement for sample with dynamic change, this spectrophotometer has adjustable spectral bandwidth of 1.0 nm to 5.0 nm. Designed compactly with fixed 2 trench sample holder, deuterium and tungsten lamp as light source, it has automatic calibration. Equipped with photomultiplier sensor, digital signal and USB interface, 4 quartz cuvette, this spectrophotometer provides high resolution, low stray light, lasting stability, and powerful software function.

Features:

- Double beam designed UV-Vis spectrophotometer
- 190 to 1100 nm of wavelength range with 1600 L/mm holographic grating
- 3D spectrogram measurement for sample with dynamic change
- Adjustable spectral bandwidth of 1.0 nm to 5.0 nm
- Fixed 2 trench sample holder, deuterium and tungsten lamp as light source
- Photomultiplier sensor, digital signal and USB interface
- 4 quartz cuvette of 10 mm optical path
- PC control software (Windows based)
- Automatic calibration
- Highly stable, User-friendly, Controlled by PC

Applications:

Double Beam UV-Vis Spectrophotometer is used for photometric measurement, spectrum scan, quantitative determination, dynamics measurement, 3D map measurement, multi-wavelength test, DNA/ Protein concentration measurement etc. across factories, schools, metallurgy, agriculture, food industry, biochemistry, environment protection, petrochemical industry, medical and health and scientific research institutes or labs etc.

Specifications:

Model No.	LD-LUS-B20
Wavelength range	190 to 1100 nm
Spectral bandwidth	1.0 to 5.0 nm (adjustable)

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Optical system	Double beam, C-T monochromator, 1600 L/mm holographic grating
Wavelength accuracy	±0.3 nm
Wavelength repeatability	0.1 nm
Wavelength resolution	0.05 nm
Wavelength edge noise	100%T line ≤0.1%T ; 0%T line ≤0.05%T
Stray light	0.015%T (at 220 nm and 360 nm)
Baseline flatness	≤±0.001 Abs
Baseline noise	±0.1%T
Baseline drift	≤0.0004 Abs / h (after warm-up at 500 nm)
Standard sample holder	Fixed 2 trench sample holder
Measuring length	0 to 200% T, -4.000 to 4.000 Abs, -9999 to 9999C, -9999 to 9999F
Transmittance accuracy	±0.3%T
Transmittance repeatability	0.1%T
Light switching point	Adjustable; 294 nm to 365 nm
Light Source	Deuterium lamp, Tungsten lamp (20 W/12 V)
Detector	Silicon photodiode detector
Interface	Digital signal; USB
Cuvette	4 quartz cuvette; 10 mm optical path
Power supply	220 V ± 10%, 50Hz
Power	200 W
Dimension (L×W×H)	620×510×245 mm
Package dimension (L×W×H)	745×635×400 mm
Net weight	30 kg
Gross weight	39 kg